

T-43-21



CD4085B Types

CMOS Dual 2-Wide 2-Input AND-OR-INVERT Gate

High-Voltage Types (20-Volt Rating)

■ CD4085 contains a pair of AND-OR-INVERT gates, each consisting of two 2-input AND gates driving a 3-input NOR gate. Individual inhibit controls are provided for both A-O-I gates.

The CD4085B types are supplied in 14-lead dual-in-line ceramic packages (D and F suffixes), 14-lead dual-in-line plastic packages (E suffix), and in chip form (H suffix).

Features:

- Medium-speed operation — $t_{PHL} = 90$ ns; $t_{PLH} = 125$ ns (typ.) at 10 V
- Individual inhibit controls
- Standardized symmetrical output characteristics
- 100% tested for quiescent current at 20 V
- Maximum input current of $1 \mu A$ at 18 V over full package-temperature range; 100 nA at 18 V and 25°C
- Noise margin (over full package-temperature range):
 - 1 V at $V_{DD} = 5$ V
 - 2 V at $V_{DD} = 10$ V
 - 2.5 V at $V_{DD} = 15$ V
- 5-V, 10-V, and 15-V parametric ratings
- Meets all requirements of JEDEC Tentative Standard No. 13B, "Standard Specifications for Description of 'B' Series CMOS Devices"

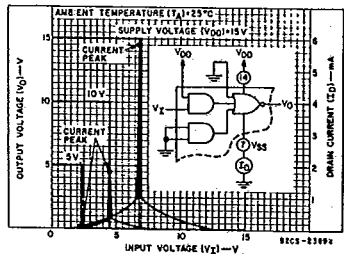
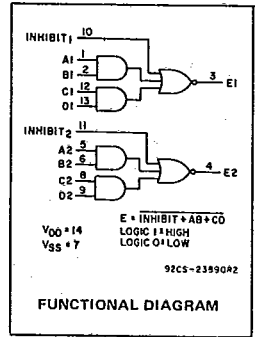


Fig. 1 - Typical voltage and current transfer characteristics.

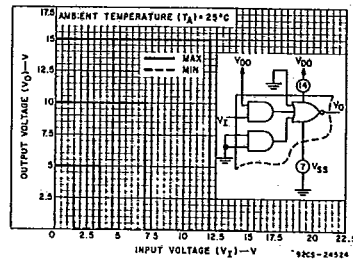


Fig. 2 - Min. and max. voltage transfer characteristics.

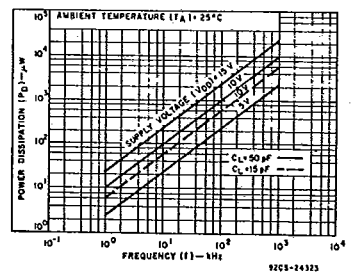


Fig. 3 - Typical power dissipation vs. frequency.

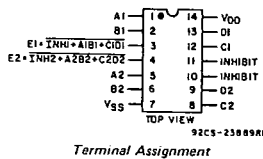
MAXIMUM RATINGS, Absolute-Maximum Values:

DC SUPPLY-VOLTAGE RANGE, (V_{DD})	-0.5V to +20V
Voltages referenced to V_{SS} Terminal)	
INPUT VOLTAGE RANGE, ALL INPUTS	-0.5V to $V_{DD} + 0.5V$
DC INPUT CURRENT, ANY ONE INPUT	± 10 mA
POWER DISSIPATION PER PACKAGE (P_D):	
For $T_A = -55^\circ C$ to $+100^\circ C$	500 mW
For $T_A = +100^\circ C$ to $+125^\circ C$	Derate Linearly at 12mW/°C to 200mW
DEVICE DISSIPATION PER OUTPUT TRANSISTOR	
For $T_A =$ FULL PACKAGE-TEMPERATURE RANGE (All Package Types)	100 mW
OPERATING-TEMPERATURE RANGE (T_A)	$-55^\circ C$ to $+125^\circ C$
STORAGE TEMPERATURE RANGE (T_{stg})	$-65^\circ C$ to $+150^\circ C$
LEAD TEMPERATURE (DURING SOLDERING):	
At distance $1/16 \pm 1/32$ inch (1.59 \pm 0.79mm) from case for 10s max	$+265^\circ C$

RECOMMENDED OPERATING CONDITIONS

For maximum reliability, nominal operating conditions should be selected so that operation is always within the following ranges:

CHARACTERISTIC	LIMITS		UNITS
	Min.	Max.	
Supply Voltage Range (For T_A = Full Package-Temperature Range)	3	18	V



COMMERCIAL CMOS
HIGH VOLTAGE ICs

CD4085B Types

T-43-21

STATIC ELECTRICAL CHARACTERISTICS

CHARACTERISTIC	CONDITIONS			LIMITS AT INDICATED TEMPERATURES (°C)							UNITS	
	V _O (V)	V _{IN} (V)	V _{DD} (V)	-55	-40	+85	+125	+25				
								Min.	Typ.	Max.		
Quiescent Device Current	—	0.5	5	1	1	30	30	—	0.02	1	μA	
I _{DD} Max.	—	0.10	10	2	2	60	60	—	0.02	2		
	—	0.15	15	4	4	120	120	—	0.02	4		
Output Low (Sink) Current, I _{OL} Min.	0.4	0.5	5	0.64	0.61	0.42	0.36	0.51	1	—	mA	
	0.5	0.10	10	1.6	1.5	1.1	0.9	1.3	2.6	—		
	1.5	0.15	15	4.2	4	2.8	2.4	3.4	6.8	—		
Output High (Source) Current, I _{OH} Min.	4.6	0.5	5	-0.64	-0.61	-0.42	-0.36	-0.51	-1	—	mA	
	2.5	0.5	5	-2	-1.8	-1.3	-1.15	-1.6	-3.2	—		
	9.5	0.10	10	-1.6	-1.5	-1.1	-0.9	-1.3	-2.6	—		
Output Voltage: Low-Level, V _{OL} Max.	—	0.5	5	0.05			—			0	0.05	V
	—	0.10	10	0.05			—			0	0.05	
	—	0.15	15	0.05			—			0	0.05	
Output Voltage: High-Level, V _{OH} Min.	—	0.5	5	4.95			4.95			5	—	V
	—	0.10	10	9.95			9.95			10	—	
	—	0.15	15	14.95			14.95			15	—	
Input Low Voltage, V _{IL} Max.	0.5, 4.5	—	5	1.5			—			—	1.5	V
	1.9	—	10	3			—			—	3	
	1.5, 13.5	—	15	4			—			—	4	
Input High Voltage, V _{IH} Min.	0.5, 4.5	—	5	3.5			3.5			—	—	V
	1.9	—	10	7			7			—	—	
	1.5, 13.5	—	15	11			11			—	—	
Input Current, I _{IN} Max.	—	0.18	18	±0.1	±0.1	±1	±1	—	±10 ⁻⁵	±0.1	μA	

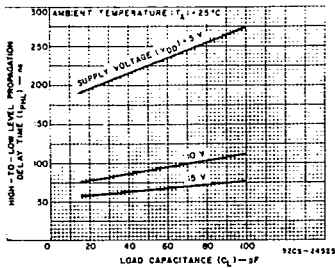


Fig. 4 - Typical data high-to-low level propagation delay time vs. load capacitance.

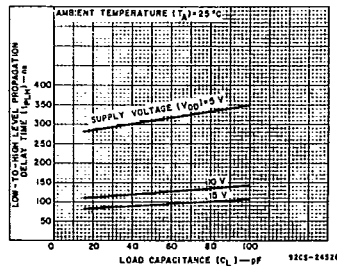


Fig. 5 - Typical data low-to-high level propagation delay time vs. load capacitance.

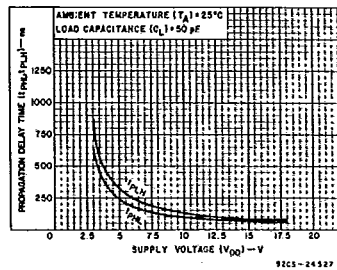


Fig. 6 - Typical data propagation delay time vs. supply voltage.

CD4085B Types

T-43-21

DYNAMIC ELECTRICAL CHARACTERISTICS at $T_A = 25^\circ\text{C}$; Input $t_r, t_f = 20 \text{ ns}$, $C_L = 50 \text{ pF}$, $R_L = 200 \text{ K}\Omega$

CHARACTERISTIC	CONDITIONS	LIMITS		UNITS
		V_{DD} V	Typ.	
Propagation Delay Time (Data): High-to-Low Level, t_{PHL}	$V_{DD} = 5$	225	450	ns
	$V_{DD} = 10$	90	180	
	$V_{DD} = 15$	65	130	
Low-to-High Level, t_{PLH}	$V_{DD} = 5$	310	620	ns
	$V_{DD} = 10$	125	250	
	$V_{DD} = 15$	90	180	
Propagation Delay Time (Inhibit): High-to-Low Level, t_{PHL}	$V_{DD} = 5$	150	300	ns
	$V_{DD} = 10$	60	120	
	$V_{DD} = 15$	40	80	
Low-to-High Level, t_{PLH}	$V_{DD} = 5$	250	500	ns
	$V_{DD} = 10$	100	200	
	$V_{DD} = 15$	70	140	
Transition Time, t_{THL}, t_{TLH}	$V_{DD} = 5$	100	200	ns
	$V_{DD} = 10$	50	100	
	$V_{DD} = 15$	40	80	
Input Capacitance, C_{IN}	Any Input	5	7.5	pF

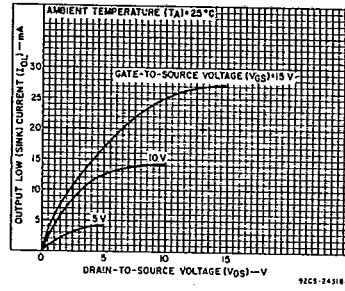


Fig. 7 - Typical output low (sink) current characteristics.

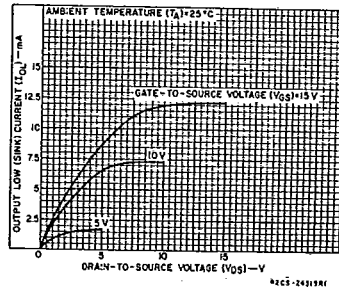


Fig. 8 - Minimum output low (sink) current characteristics.

COMMERCIAL CMOS
HIGH VOLTAGE ICs

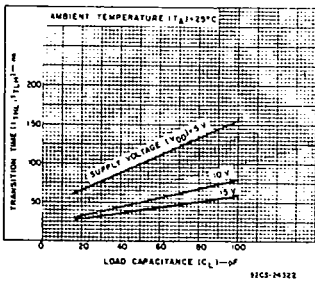


Fig. 9 - Typical transition time vs. load capacitance.

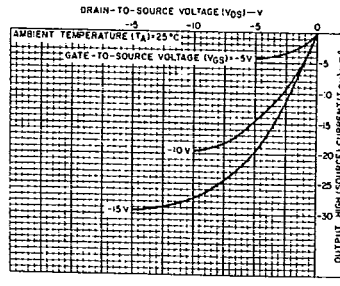


Fig. 10 - Typical output high (source) current characteristics.

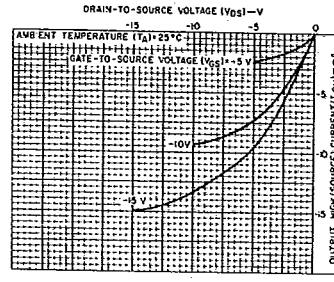


Fig. 11 - Minimum output high (source) current characteristics.

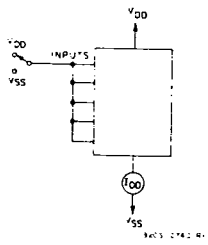


Fig. 12 - Quiescent device current test circuit.

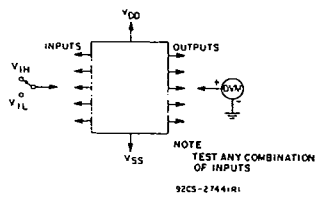


Fig. 13 - Input voltage test circuit.

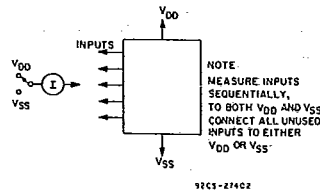


Fig. 14 - Input current test circuit.

CD4085B Types

T-43-21

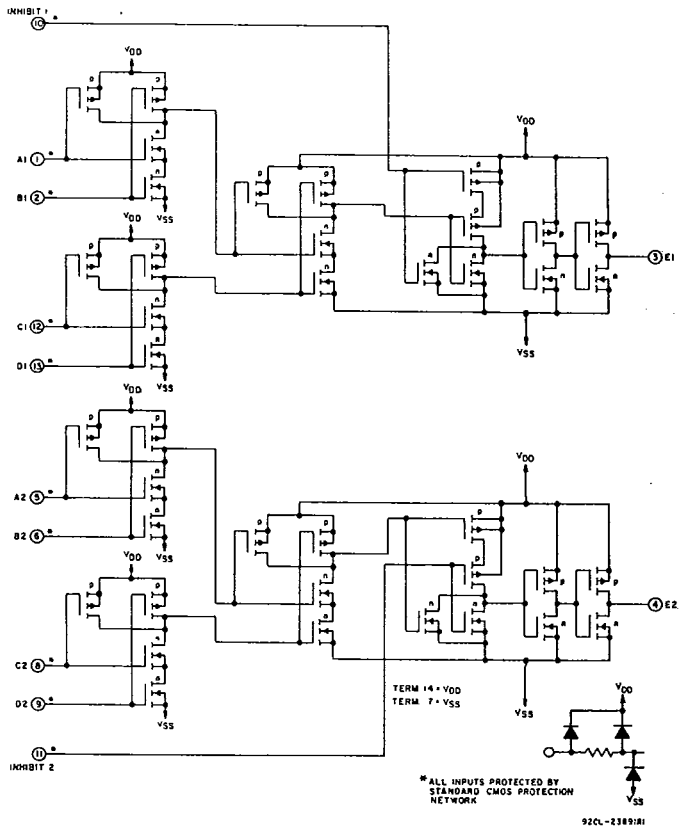
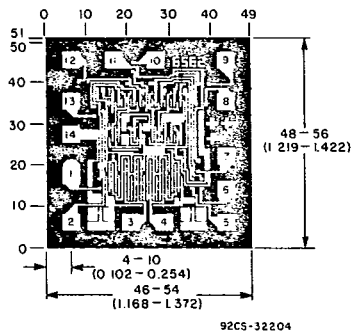


Fig. 15 - CD4085 schematic diagram.



Dimensions in parentheses are in millimeters and are derived from the basic inch dimensions as indicated. Grid graduations are in mils (10^{-3} inch).

92CS-32204

Dimensions and Pad Layout for CD4085BH.